



Fig. 5. (Media 1) Demonstration of ankylography with a high-NA diffraction pattern. (a) Diffraction pattern mapped onto the surface of the Ewald sphere accompanied by a projection onto the plane. (b) Isosurface rendering of the 3-D ankylographic reconstruction. (c) Same as in (b) showing tilt of sample with respect to the detector. (d) Same as in (b) showing the relative size difference between features in the sample with emphasis in the z-direction, accompanied by a projection onto the plane.

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